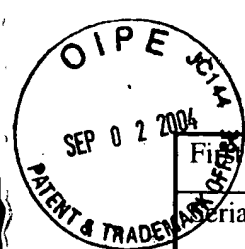


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| First Named Inventor | Leonard Forbes | GENERAL TRANSMITTAL FORM UNDER 37 CFR 1.8 (LARGE ENTITY) |
| Serial No. | 10/775,908 | |
| Filing Date | February 10, 2004 | |
| Group Art Unit | 2818 | |
| Examiner Name | Unknown | |
| Confirmation No. | 1212 | |
| Attorney Docket No. | 400.272US01 | |
| Title: NROM FLASH MEMORY WITH A HIGH-PERMITTIVITY GATE DIELECTRIC | | |

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| Enclosures | | | | | |
| The following documents are enclosed: | | | | | |
| <input checked="" type="checkbox"/> | Information Disclosure Statement (1 pg.); Form 1449 (7 pgs.); 58 copies of cited references; U.S. reference(s) not included pursuant to 37 C.F.R. 1.98 (c)(2)(i); | | | | |
| <input checked="" type="checkbox"/> | An itemized return-receipt postcard | | | | |
| Leffert Jay & Polglaze, P.A. P.O. Box 581009 Minneapolis, MN 55458-1009 T - 612/312-2200 F - 612/312-2250 | | | | | |
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| Name | Kenneth W. Bolvin | Reg. No. | 34,125 | Telephone | (612) 312-2211 |
| Signature | | | | Date | 8/31/04 |
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| I certify that this correspondence and the identified documents listed on this transmittal are being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Mail Stop: AMENDMENT, Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450 on August 31, 2004. | | | | | |
| Name | Rhonda L. Foley | | Signature | | |

(LARGE ENTITY TRANSMITTAL UNDER 37 CFR § 1.8)



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|---|-------------------|---|
| Filed Named Inventor | Leonard Forbes | INFORMATION DISCLOSURE STATEMENT |
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Alexandria, VA 22313-1450

In compliance with 37 C.F.R. §§ 1.56 and 1.97, *et seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified Application.

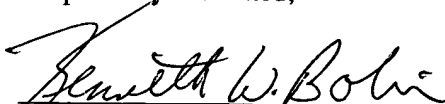
Pursuant to 37 C.F.R. 1.98 (a)(2)(i), as this application was filed after June 30, 2003, Applicant has not included copies of U.S. Patents or U.S. Patent Applications. Applicant respectfully requests that this Information Disclosure Statement be entered and the references listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to MPEP §609, Applicant further requests that the Examiner initial next to each reference on the Form 1449 to indicate that the listed references have been considered. Applicant further requests that a copy of the initialed Form 1449 be returned with the next official communication.

As an Office Action has not yet issued in this application, Applicant believes that no fees are due. However, the Commissioner for Patents is hereby authorized to charge any additional fees to Deposit Account No. 501373.

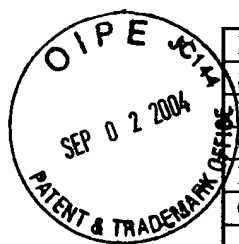
If the Examiner has any questions or concerns regarding this application, please contact the undersigned at (612) 312-2211.

Respectfully submitted,

Date: 8/31/04


Kenneth W. Bolvin
Reg. No. 34,125

Attorneys for Applicant
Leffert Jay & Polglaze
P.O. Box 581009
Minneapolis, MN 55458-1009
T 612 312-2200
F 612 312-2250



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| First Named Inventor | Leonard Forbes | INFORMATION DISCLOSURE STATEMENT FORM PTO-1449 |
| Serial No. | 10/775,908 | |
| Filing Date | February 10, 2004 | |
| Group Art Unit | 2818 | |
| Examiner Name | Unknown | |
| Confirmation No. | 1212 | |
| Attorney Docket No. | 400.272US01 | |
| Title: NROM FLASH MEMORY WITH HIGH-PERMITTIVITY GATE DIELECTRIC | | Sheet 1 of 7 |

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|---|-------------------|---|
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| Serial No. | 10/775,908 | |
| Filing Date | February 10, 2004 | |
| Group Art Unit | 2818 | |
| Examiner Name | Unknown | |
| Confirmation No. | 1212 | |
| Attorney Docket No. | 400.272US01 | |
| Title: NROM FLASH MEMORY WITH HIGH-PERMITTIVITY GATE DIELECTRIC | | Sheet 3 of 7 |

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| Examiner Initials | Foreign Patent | | Name | Publication Date | Translation |
| | Country | No. | | | |
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